

Calculation of testability measures on structurally synthesized binary decision diagrams

Ubar, Raimund-Johannes; Heinlaid, J.; Raik, Jaan; Raun, L. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 179-182: ill

Improved testability calculation for digital circuits

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